



Chuangxin Online Test Center Laboratory

Add: F/r 401 Building A, Ying Da Feng industrial No,393,Jihua Rd.LongGang
Dis. Shenzhen China
Tel: 0755-83762185 Email: engineer@iclab-cn.com



Report No:	SZ12092020005
Date:	2020/12/09
Page:	1/8

Project Inspection Report

Company : N/A
Address : N/A
Sample Name : XC3S400-4FTG256C
Manufacture : XILINX
Date Code : 2005
Package Type : BGA-256
Sample Number : 5 PCS
Check Number : 5 PCS
Date of Received : 12/05/2020
Date of Tested : 9:00/12/05/2020~12:00/12/09/2020

WE HEREBY CERTIFY THAT:

The test(s) shown in the attachment were conducted according to the indicating procedures. We assume full responsibility for the accuracy and completeness of these tests and vouch for the qualifications of all personnel performing them.

Inspected by Engineer
Star_Wu

Reviewed by Project Manager
Lucy

Note:

1. This report will be invalid if reproduced in whole or in part.
2. This report refers only to the specimen(s) submitted to test, and is invalid if used separately.
3. This report is only valid with the examination seal and signature of this institute.
4. The tested specimen(s) will only be preserved for thirty days from the date issued, if not collected by the applicant.
5. This report is only responsible for the samples tested.



Chuangxin Online Test Center Laboratory

Add: F/r 401 Building A, Ying Da Feng industrial No,393,Jihua Rd.LongGang
Dis. Shenzhen China
Tel: 0755-83762185 Email: engineer@iclab-cn.com



Report No:	SZ12092020005
Date:	2020/12/09
Page:	2/8

Items test

- External visual inspection
- Pin Correlation Test
- Programming test
- Solder ability Analysis
- Radiography (X-ray)
- ROHS test
- Key Functional Testing (KFT)
- Baking
- Tape and Reel
- Internal visual inspection

Methods & Equipment

1.1 Applicable Standard

- GB/T 17574-1998 IV 3-6

1.2 Optical Microscope

- Equipment Spec:
Top view: FINIAL Hi-scope System SEZ-260: X7 ~ X45
FJ-3A: X50 ~ X500

1.3 Functional testing Equipment

- ISE Design Suite 14.7
- JTAG configuration mode
- Platform Cable USB

1.4 Testing Environment

- Ambient Temperature: 25±5°C
- Relative Humidity: 45%-65% RH

1.5 Testing Base

- XILINX XC3S400-4FTG256C

https://china.xilinx.com/support/documentation/data_sheets/ds099.pdf



Chuangxin Online Test Center Laboratory

Add: F/r 401Building A, Ying Da Feng industrial No,393,Jihua Rd.LongGang
Dis. Shenzhen China
Tel: 0755-83762185 Email: engineer@iclab-cn.com



Report No:	SZ12092020005
Date:	2020/12/09
Page:	3/8

Analysis Summary

Key Functional Testing (KFT) Results:

Key Functional Testing (KFT)	Results:
Total quantity tested:	5 pcs
Total quantity passed:	5 pcs
Total quantity failed:	0 pcs
Note:	All devices passed the parameter test.

Key Functional Testing (KFT) Results:

Tested Parameters	Results
JTAG configuration mode	Pass
Programming test	Pass
ID Code check	Pass

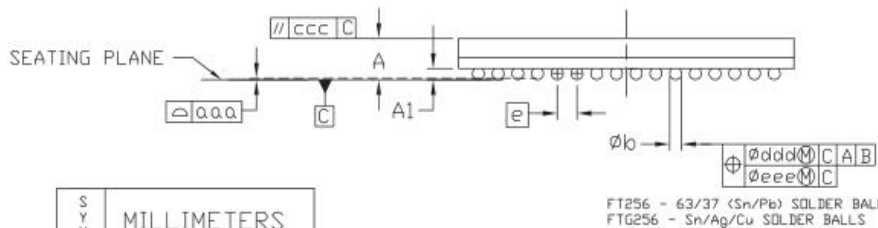
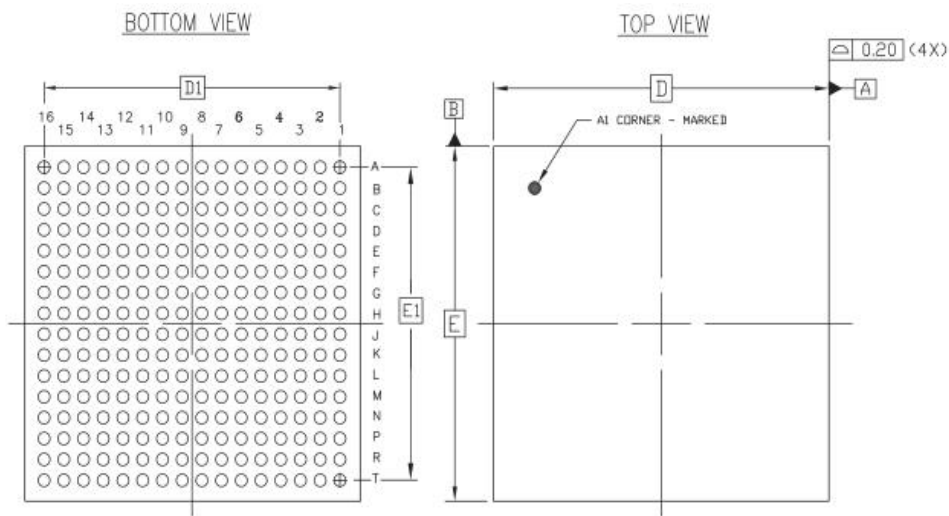


Report No:	SZ12092020005
Date:	2020/12/09
Page:	4/8

1. Device Description:

The Spartan®-3 family of Field-Programmable Gate Arrays is specifically designed to meet the needs of high volume, cost-sensitive consumer electronic applications.

2. Package Dimensions:



SYMBOL	MILLIMETERS		
	MIN.	NOM.	MAX.
A	<i>h</i>	1.40	1.55
A ₁	0.30	0.40	0.50
$\frac{D1}{E1}$	17.00 BSC		
$\frac{D}{E}$	15.00 REF		
$\frac{E}{E1}$	1.00 BSC		
ϕb	0.40	0.50	0.60
aaa	<i>h</i>	<i>h</i>	0.20
ccc	<i>h</i>	<i>h</i>	0.15
ddd	<i>h</i>	<i>h</i>	0.25
eee	<i>h</i>	<i>h</i>	0.10
M	16		

FT256 - 63/37 (Sn/Pb) SOLDER BALLS
 FTG256 - Sn/Ag/Cu SOLDER BALLS

NOTES:

1. ALL DIMENSIONS AND TOLERANCES CONFORM TO ASME Y14.5M-1994
2. SYMBOL 'M' IS THE BALL MATRIX SIZE.
3. CONFORMS TO JEDEC MS-034 AAF-1 EXCEPT FOR THE SOLDER BALL SIZE.



Chuangxin Online Test Center Laboratory

Add: F/r 401Building A, Ying Da Feng industrial No,393,Jihua Rd.LongGang
Dis. Shenzhen China
Tel: 0755-83762185 Email: engineer@iclab-cn.com



Report No:	SZ12092020005
Date:	2020/12/09
Page:	5/8

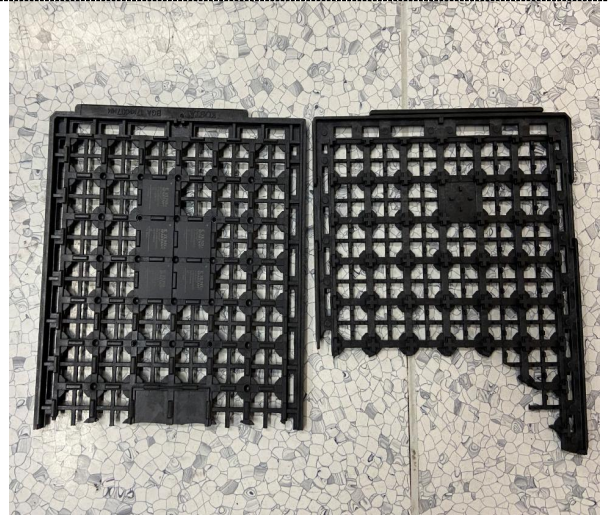
3. Receiving Inspection:

Gross Weight	106 g	Parts Total	5 PCS
Number Of Boxes	N/A	Intact Label	Non Present
Package type	Bulk	Moisture protection	Non Present
MSL	N/A	ESD protection	Non Present

Received View-1



Received View-2





Chuangxin Online Test Center Laboratory

Add: F/r 401Building A, Ying Da Feng industrial No.393,Jihua Rd.LongGang
Dis. Shenzhen China
Tel: 0755-83762185 Email: engineer@iclab-cn.com


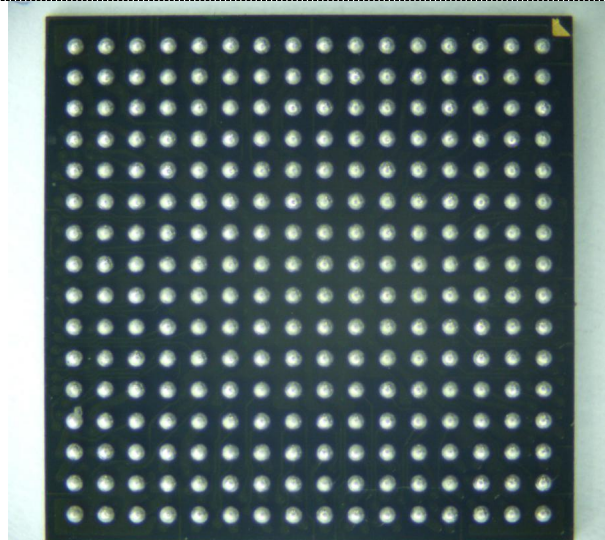
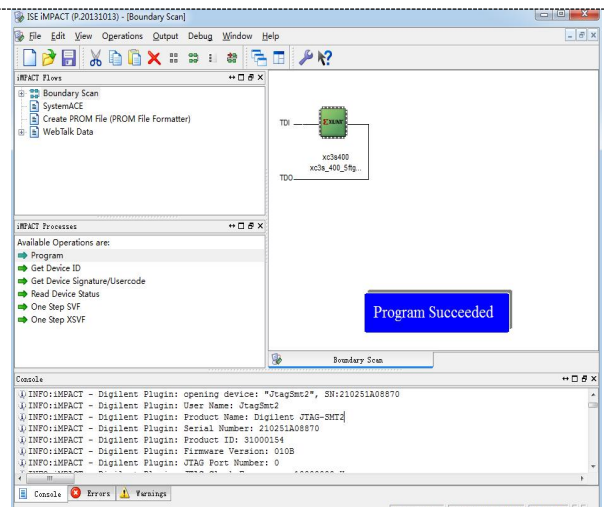
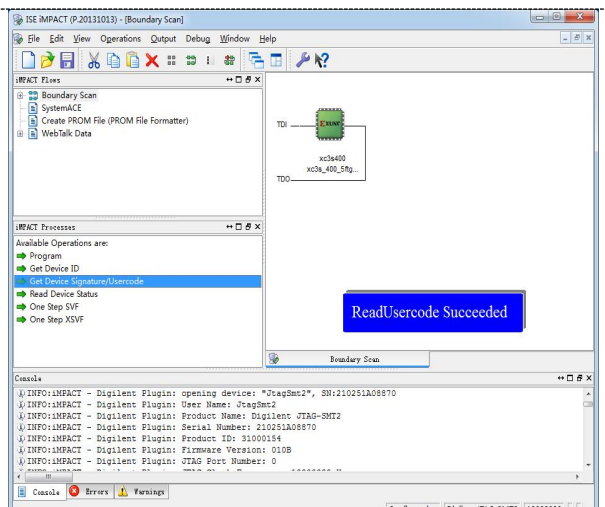


Report No:	SZ12092020005
Date:	2020/12/09
Page:	6/8

4. Key Functional Testing (KFT):

Using ISE Design Suite 14.7, JTAG connector verified the following parameters at TA = 25°C:

- JTAG configuration mode.
- Programming test.
- ID Code checked.

<p style="text-align: center;">Top</p>  <p style="text-align: center;">Program Succeeded</p>	<p style="text-align: center;">Bottom</p>  <p style="text-align: center;">ReadUserCode Succeeded</p>
 <p style="text-align: center;">Program Succeeded</p>	 <p style="text-align: center;">ReadUserCode Succeeded</p>



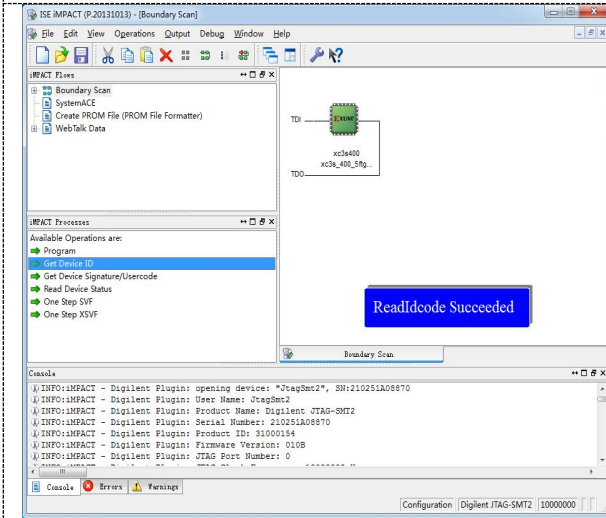
Chuangxin Online Test Center Laboratory

Add: F/r 401Building A, Ying Da Feng industrial No,393,Jihua Rd.LongGang
 Dis. Shenzhen China
 Tel: 0755-83762185 Email: engineer@iclab-cn.com

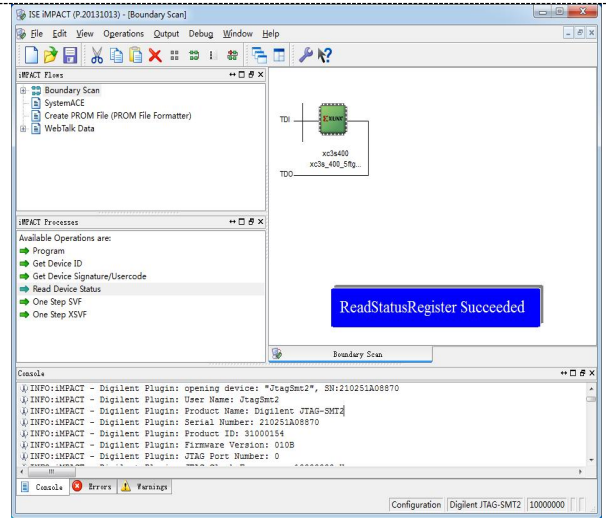


Report No:	SZ12092020005
Date:	2020/12/09
Page:	7/8

ReadIdcode Succeeded



ReadStatusRegister Succeeded



Key Functional Testing (KFT) Results:

Key Functional Testing (KFT)	Results:
Total quantity tested:	5 pcs
Total quantity passed:	5 pcs
Total quantity failed:	0 pcs
Note:	All devices passed the parameter test.

End



Chuangxin Online Test Center Laboratory

Add: F/r 401Building A, Ying Da Feng industrial No,393,Jihua Rd.LongGang
Dis. Shenzhen China
Tel: 0755-83762185 Email: engineer@iclab-cn.com



Report No:	SZ12092020005
Date:	2020/12/09
Page:	8/8

For more information, please visit: <https://www.iclab-cn.com>

CXO Lab WeChat official account

